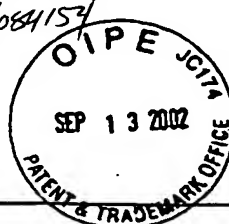


	ATTY. DOCKET NO. 2000P03099WOUS	SERIAL NO. 10/084153
		
	APPLICANT Siemens Aktiengesellschaft	
FILING DATE		GROUP

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EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>MS</i>	AA	4,595,340	17.Jun. 1986	Klassen David			
	AB	5,407,326	18. April 1995	Lerdellier, Alain			
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FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
<i>MS</i>	AD	EP 0,924,381	23. Jun. 1999	EPO			

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		RECEIVED SEP 17 2002 GROUP 3600
EXAMINER	<i>Paul Jones</i>	DATE CONSIDERED 3/11/06
EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

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<p>Form PTO-1449</p> <p>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</p> <p>(Use several sheets if necessary)</p>	<p>ATTY DOCKET NO. 32860-000280/US</p>	<p>APPLICATION NO. 10/084,154</p>
	<p>APPLICANT Christiane FOERTSCH et al.</p>	<p>CONF. NO. 4901</p>
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DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
					YES	NO
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OTHER DOCUMENTS (Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume- issue number(s), publisher, city and/or country where published.

	WOLFGANG KÄFER ET AL.: "Konfigurierungskonzepte für DB-basierte technisch Entwurfsanwendungen", <u>Informatik Forschung und Entwicklung</u> , pp. 1-17, 1998.	7
78	PETER VAN DEN HAMER ET AL.: "Managing Design Data: The Five Dimensions of CAD Frameworks, Configuration Management, and Product Data Management", <u>Proceedings of the IEEE</u> , Vol. 84, No. 1, pp. 42-56, January 1996.	
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